

Appl. No. 10/037,707
Amdt. Dated January 28, 2005
Reply to Office action of October 29, 2004

Amendments to the Abstract:

Please replace the Abstract with the following rewritten Abstract:

A docking system (10) and method for docking a test head (16) of a device tester to a device handler. The docking system (10) has a handler plate (12) and a tester plate (14), respectively mountable to the device handler and the test head (16). The handler plate (12) has two conversion bars (18a, 18b). Each of the two conversion bars (18a,18b) has two lateral protrusions (40a,40b). The tester plate (140 has four slot mounts (26a,26b,26c,26d), each with an escalating slot (50) that is laterally oriented for respective linear engagement with the lateral protrusions (40a,40b) for the docking. The method involves making a quick alignment of the handler plat (12) to the tester plate (14) by inserting two pre-docking guide pins into (20a,20b) two pin sockets (22a,22b) and, thereafter, actuating one or both of two actuating cams (28a,28b) for the respective linear engagement.

-FIG.1 accompanies the abstract.